# **BLF7G21LS-160**

# **Power LDMOS transistor**

Rev. 1 — 20 April 2012

**Product data sheet** 

# 1. Product profile

#### 1.1 General description

160 W LDMOS power transistor for base station applications at frequencies from 1800 MHz to 2050 MHz.

Table 1. Typical performance

Typical RF performance at  $T_{\text{case}}$  = 25 °C in a common source class-AB production test circuit.

Mode of operation	f	$I_{Dq}$	$V_{DS}$	$P_{L(AV)}$	$G_p$	$\eta_{\text{D}}$	ACPR
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	1930 to 1990	1080	28	45	18	34	–30 <u>[1]</u>
1-carrier W-CDMA	1930 to 1990	1080	28	50	18	36	-34 <sup>[2]</sup>

<sup>[1]</sup> Test signal: 3GPP; test model 1; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on CCDF; carrier spacing 5 MHz.

#### 1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R<sub>th</sub> providing excellent thermal stability
- Designed for broadband operation (1800 MHz to 2050 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

### 1.3 Applications

 RF power amplifiers for base stations and multi carrier applications in the 1800 MHz to 2050 MHz frequency range



<sup>[2]</sup> Test signal: 3GPP; test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF.

# 2. Pinning information

Table 2. Pinning

Pin Description  1 drain  2 drain  3 gate  4 gate  5 source  [1]  Simplified outline Graphic symbol	Table 2.	ı illililiğ			
2 drain 3 gate 4 gate 5 source  1 2 3 4 5	Pin	Description		Simplified outline	Graphic symbol
3 gate 4 gate 5 source  11  3 4	1	drain			
4 gate 5 source  11 3 4	2	drain			
5 source 11 3 4	3	gate			
5 source [1] 4 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1	4	gate		5	- 1 - 1
dad=001924	5	source	<u>[1]</u>	3 4	4

<sup>[1]</sup> Connected to flange.

# 3. Ordering information

Table 3. Ordering information

Type number	Packag	ge	
	Name	Description	Version
BLF7G21LS-160	-	earless flanged LDMOST ceramic package; 4 leads	SOT1121B

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	65	V
$V_{GS}$	gate-source voltage		-0.5	+13	V
T <sub>stg</sub>	storage temperature		-65	+150	°C
T <sub>i</sub>	junction temperature		-	200	°C

## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{\text{th(j-c)}}$	thermal resistance from junction to case	$T_{case}$ = 80 °C; $P_L$ = 100 W	0.41	K/W

### 6. Characteristics

Table 6. Characteristics

 $T_i = 25 \, ^{\circ}\text{C}$ .

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 1.8 \text{ mA}$	65	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_{D} = 180 \text{ mA}$	1.5	1.9	2.3	V
I <sub>DSS</sub>	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	2.8	μΑ
I <sub>DSX</sub>	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	34	-	Α
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	280	nA
9 <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_{D} = 9 \text{ A}$	-	13	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 6.3 \text{ A}$	-	80.0	-	Ω

### 7. Test information

#### Table 7. Application information

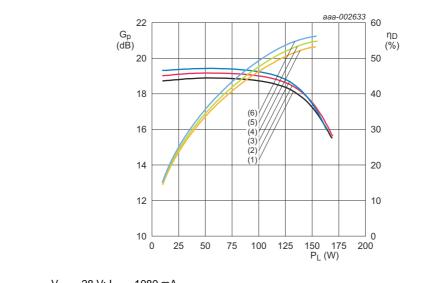
Mode of operation: 2-carrier W-CDMA; PAR 8.4 dB at 0.01 % probability on CCDF; 3GPP test model 1; 64 PDPCH;  $f_1$  = 1932.5 MHz;  $f_2$  = 1937.5 MHz;  $f_3$  = 1982.5 MHz;  $f_4$  = 1987.5 MHz; RF performance at  $V_{DS}$  = 28 V;  $I_{Dq}$  = 1080 mA;  $T_{case}$  = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$G_p$	power gain	$P_{L(AV)} = 45 \text{ W}$	17.0	18.0	-	dB
RLin	input return loss	$P_{L(AV)} = 45 \text{ W}$	-	-15	-8	dB
$\eta_{D}$	drain efficiency	$P_{L(AV)} = 45 \text{ W}$	31	34	-	%
ACPR <sub>5M</sub>	adjacent channel power ratio (5 MHz)	$P_{L(AV)} = 45 \text{ W}$		-30	-25	dBc

### 7.1 Ruggedness in class-AB operation

The BLF7G21LS-160 is capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions:  $V_{DS}$  = 28 V;  $I_{Dq}$  = 1080 mA;  $P_L$  = 160 W (CW); f = 1805 MHz.

### 7.2 1-Tone CW

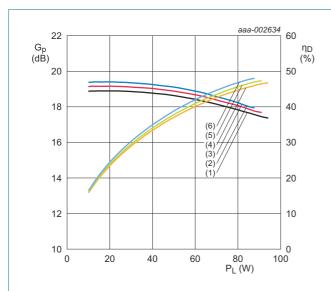


 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1)  $G_p$  at f = 1930 MHz
- (2)  $G_p$  at f = 1960 MHz
- (3)  $G_p$  at f = 1990 MHz
- (4)  $\eta_D$  at f = 1930 MHz
- (5)  $\eta_D$  at f = 1960 MHz
- (6)  $\eta_D$  at f = 1990 MHz

Power gain and drain efficiency as function of load power; typical values Fig 1.

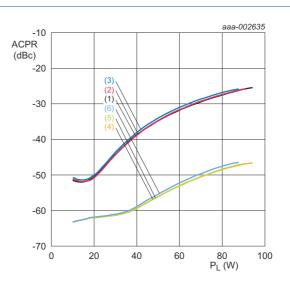
#### 7.3 1-Carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1)  $G_p$  at f = 1930 MHz
- (2)  $G_p$  at f = 1960 MHz
- (3)  $G_p$  at f = 1990 MHz
- (4)  $\eta_D$  at f = 1930 MHz
- (5)  $\eta_D$  at f = 1960 MHz
- (6)  $\eta_D$  at f = 1990 MHz

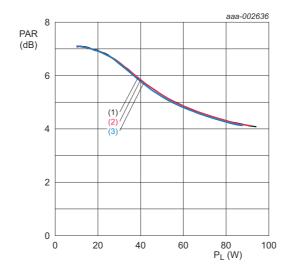
Fig 2. Power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1) ACPR<sub>5M</sub> at f = 1930 MHz
- (2) ACPR<sub>5M</sub> at f = 1960 MHz
- (3) ACPR<sub>5M</sub> at f = 1990 MHz
- (4) ACPR<sub>10M</sub> at f = 1930 MHz
- (5) ACPR<sub>10M</sub> at f = 1960 MHz
- (6) ACPR<sub>10M</sub> at f = 1990 MHz

Fig 3. Adjacent channel power ratio (5 MHz) and Adjacent channel power ratio (10 MHz) as a function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1) f = 1930 MHz
- (2) f = 1960 MHz
- (3) f = 1990 MHz

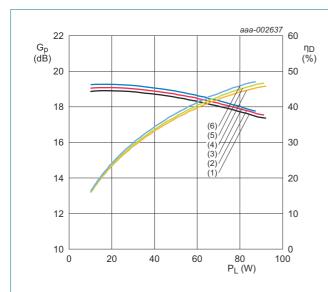
Fig 4. Peak-to-average ratio as a function of load power; typical values

BLF7G21LS-160

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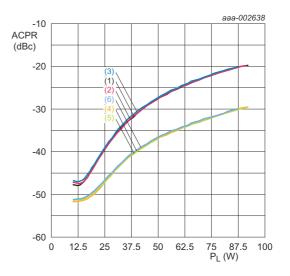
### 7.4 2-Carrier W-CDMA at 5 MHz carrier spacing



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1)  $G_p$  at f = 1930 MHz
- (2)  $G_p$  at f = 1960 MHz
- (3)  $G_p$  at f = 1990 MHz
- (4)  $\eta_D$  at f = 1930 MHz
- (5)  $\eta_D$  at f = 1960 MHz
- (6)  $\eta_D$  at f = 1990 MHz

Fig 5. Power gain and drain efficiency as function of load power; typical values



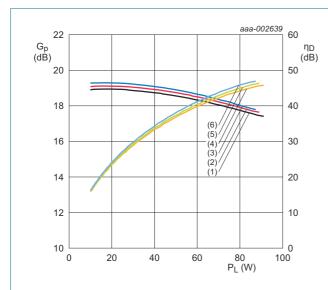
 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1) ACPR<sub>5M</sub> at f = 1930 MHz
- (2) ACPR<sub>5M</sub> at f = 1960 MHz
- (3) ACPR<sub>5M</sub> at f = 1990 MHz
- (4) ACPR<sub>10M</sub> at f = 1930 MHz
- (5) ACPR<sub>10M</sub> at f = 1960 MHz
- (6) ACPR<sub>10M</sub> at f = 1990 MHz

Fig 6. Adjacent channel power ratio (5 MHz) and adjacent channel power ratio (10 MHz) as a function of load power; typical values

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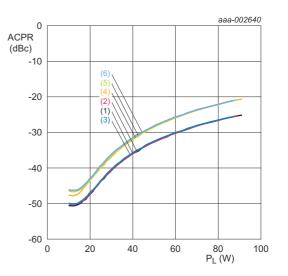
## 7.5 2-Carrier W-CDMA at 10 MHz carrier spacing



 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1)  $G_p$  at f = 1930 MHz
- (2)  $G_p$  at f = 1960 MHz
- (3)  $G_p$  at f = 1990 MHz
- (4)  $\eta_D$  at f = 1930 MHz
- (5)  $\eta_D$  at f = 1960 MHz
- (6)  $\eta_D$  at f = 1990 MHz

Fig 7. Power gain and drain efficiency as function of load power; typical values

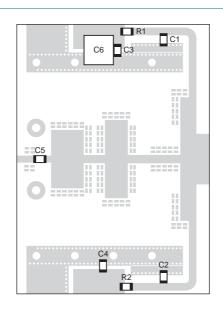


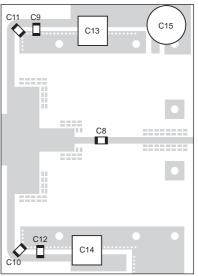
 $V_{DS} = 28 \text{ V}; I_{Dq} = 1080 \text{ mA}.$ 

- (1) ACPR<sub>5M</sub> at f = 1930 MHz
- (2) ACPR<sub>5M</sub> at f = 1960 MHz
- (3) ACPR<sub>5M</sub> at f = 1990 MHz
- (4) ACPR<sub>10M</sub> at f = 1930 MHz
- (5) ACPR<sub>10M</sub> at f = 1960 MHz
- (6) ACPR<sub>10M</sub> at f = 1990 MHz

Fig 8. Adjacent channel power ratio (5 MHz) and adjacent channel power ratio (10 MHz) as a function of load power; typical values

#### 7.6 Test circuit





aaa-002770

Printed-Circuit Board (PCB): Taconic RF35;  $\epsilon_{r}$  = 3.5; thickness = 0.76 mm; thickness copper plating = 35  $\mu m$ .

See Table 8 for a list of components.

Fig 9. Component layout for class-AB production test circuit

**Table 8.** List of components For test circuit see Figure 9.

Component	Description	Value	Remarks
C1, C2, C5, C9, C10	multilayer ceramic chip capacitor	68 pF	[1]
C3, C4, C11, C12	multilayer ceramic chip capacitor	820 pF	[2]
C6, C13, C14	multilayer ceramic chip capacitor	10 μF	[3]
C8	multilayer ceramic chip capacitor	10 pF	[1]
C15	electrolytic capacitor	470 μF; 63 V	
R1, R2	SMD resistor	12 Ω	Philips 1206

- [1] American Technical Ceramics type 800B or capacitor of same quality.
- [2] American Technical Ceramics type 100A or capacitor of same quality.
- [3] TDK or capacitor of same quality.

# 7.7 Impedance information

Table 9. Typical impedance

Typical values valid for both section in parallel;  $I_{Dq} = 1800$  mA;  $V_{DS} = 28$  V, unless otherwise specified.

<del>-</del>		
f	Z <sub>S</sub>	Z <sub>L</sub>
MHz	Ω	Ω
1750	0.99 - j4.09	2.32 – j2.35
1805	1.12 – j4.39	2.20 – j2.20
1840	1.23 – j4.58	2.08 – j2.14
1880	1.31 – j4.74	1.94 – j2.12
1930	1.49 – j5.01	1.76 – j2.15
1960	1.61 – j5.19	1.66 – j2.20
1990	1.75 – j5.36	1.56 – j2.26
2020	1.91 – j5.54	1.48 – j2.34
2050	2.13 – j5.75	1.4 – j2.42

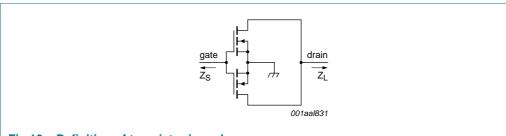


Fig 10. Definition of transistor impedance

# 8. Package outline

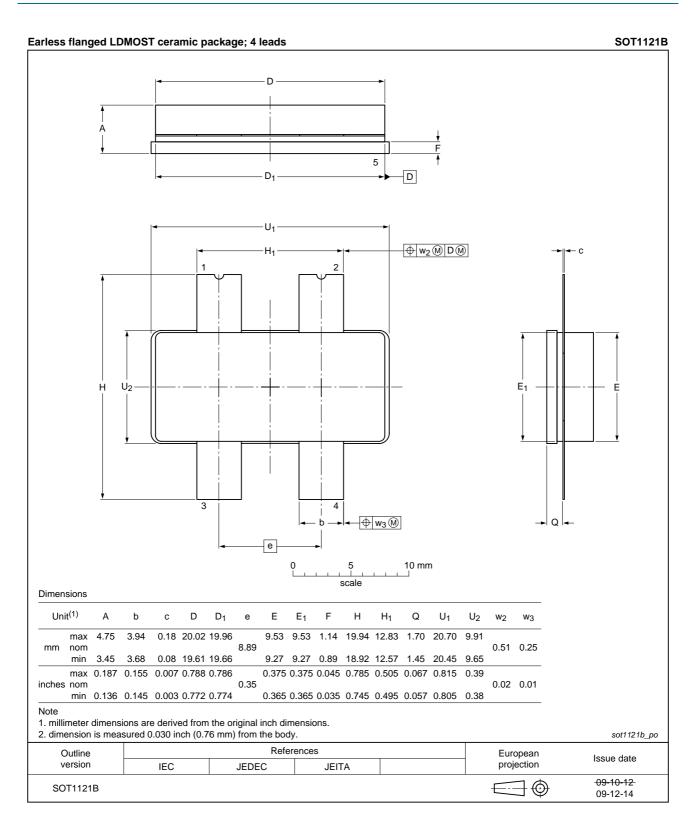


Fig 11. Package outline SOT1121B

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# 9. Abbreviations

Table 10. Abbreviations

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
LDMOS	Laterally Diffused Metal Oxide Semiconductor
LDMOST	Laterally Diffused Metal Oxide Semiconductor Transistor
PAR	Peak-to-Average Ratio
PDPCH	transmission Power of the Dedicated Physical CHannel
RF	Radio Frequency
SMD	Surface Mounted Device
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

# 10. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF7G21LS-160 v.1	20120420	Product data sheet	-	-

## 11. Legal information

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Document status[1][2]	Product status[3]	Definition
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